

SYSTEM INITIALIZATION OF MICROCODE-BASED
MEMORY BUILT-IN SELF-TEST

ABSTRACT OF THE DISCLOSURE

The functionality of a programmable memory built-in self-test (BIST) arrangement for testing an embedded memory structure of an integrated circuit is extended to system level testing to ascertain 5 operability of the system after the integrated circuits and boards including them have been placed in service in larger systems, by generating default test signals which are loaded in an instruction store module when test instructions are not provided from an external tester. This additional utility of 10 the BIST arrangement, increases efficiency of chip space utilization and improves the system level test. Loading of test instructions from an external tester during chip manufacture and/or board assembly 15 is unaffected.